

FORM PTO-1449 (Modified)	JUN 28 2006 RECEIVED U.S. PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. IS920030247US1	SERIAL NO. 10/605,672
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		APPLICANT: Bruce B. Doris, et al.	
(Use several sheets if necessary)		FILING DATE: 10/16/03	GROUP: 2812

**REFERENCE DESIGNATION**                    **U.S. PATENT DOCUMENTS**

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
SDI	6,228,694 B1	5/8/2001	Doyle et al.			
	6,406,973 B1	6/18/2002	Lee			
	6,281,532 B1	8/28/2001	Doyle et al.			
	5,683,934	11/4/97	Candelaria			
	6,368,931 B1	4/9/2002	Kuhn, et al.			
	5,310,446	5/10/94	Konishi et al.			
	4,853,076	8/1/89	Tsaur et al.			
	US 2002/0090791 A1	7/11/2002	Doyle et al.			
	US 2002/0074598 A1	6/20/2002	Doyle et al.			
	6,509,618 B2	7/21/2003	Jan et al.			
	6,476,462 B2	11/5/2002	Shimizu et al.			
	6,362,082 B1	3/26/2002	Doyle et al.			
	6,228,694 B1	5/8/2001	Doyle et al.			
	5,565,697	10/15/96	Asakawa et al.			
	US 2003/0040158 A1	2/27/2003	Saitoh			
	US 2002/0086472 A1	7/4/2002	Roberds et al.			
	6,521,964 B1	2/18/2003	Jan et al.			
	6,506,652	01/14/03	Jan, et al.			

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES
						NO

**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

EXAMINER Annetta Baac DATE CONSIDERED 4/30/05

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EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO)	
SDT	5,081,513	1/14/1992	Jackson, et al.				
	3,602,841	8/31/1971	McGroddy				
	6,531,740	3/11/2003	Bosco, et al.				
	6,531,369	3/11/2003	Ozkan, et al.				
	6,501,121	12/31/2002	Yu, et al.				
	6,498,358	12/24/2002	Lach, et al.				
	6,493,497	12/10/2002	Ramdani, et al.				
	6,403,975	6/11/2002	Brunner, et al.				
	6,361,885	3/26/2002	Chou				
	6,255,169	7/3/2001	Li, et al.				
	6,246,095	6/12/2001	Brady, et al.				
	6,165,383	12/26/2000	Chou				
	6,133,071	10/17/2000	Nagai				
	6,046,464	4/4/2000	Schetzina				
	6,025,280	2/15/2000	Brady, et al.				

## FOREIGN PATENT DOCUMENTS

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<i>Shanell Loe</i>	4/30/05

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EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)	
SDS	5,940,736	8/17/1999	Brady, et al.				
	5,880,040	3/9/1999	Sun, et al.				
	5,861,651	1/19/1999	Brasen, et al.				
	5,679,965	10/21/1997	Schetzina				
	5,670,798	9/23/1997	Schetzina				
	5,561,302	10/1/1996	Candelaria				
	5,471,948	12/5/1995	Burroughes, et al.				
	5,459,346	10/17/1995	Asakawa, et al.				
	5,391,510	2/21/1995	Hsu, et al.				
	5,371,399	12/6/1994	Burroughes, et al.				
	5,108,843	4/28/1992	Ohtaka, et al.				
	5,060,030	10/22/1991	Hoke				
	4,958,213	9/18/1990	Eklund, et al.				
	4,665,415	5/12/1987	Esaki, et al.				

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<i>Stanette lace</i>	4/30/05

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EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
SDF	5,989,978	11/23/1999	Peidous			
	6,284,626	9/4/2001	Kim			
	6,274,444	8/14/2001	Wang			
	6,261,964	7/17/2001	Wu, et al.			
	6,221,735	4/24/2001	Manley, et al.			
	6,117,722	9/12/2000	Wuu, et al.			
	6,107,143	8/22/2000	Park, et al.			
	6,090,684	7/18/2000	Ishitsuka, et al.			
	6,066,545	5/23/2000	Doshi, et al.			
	6,008,126	12/28/1999	Leedy			
	5,946,559	8/31/1999	Leedy			
	5,840,593	11/24/1998	Leedy			
	5,592,018	1/7/1997	Leedy			
	5,592,007	1/7/1997	Leedy			
	5,571,741	11/5/1996	Leedy			

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EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROD)
SPT	5,557,122	9/17/1996	Shrivastava, et al.			
	5,354,695	10/11/1994	Leedy			
	5,134,085	7/28/1992	Gilgen, et al.			
	5,006,913	4/9/1991	Sugahara, et al.			
	4,952,524	8/28/1990	Lee, et al.			
	4,855,245	8/8/1989	Neppl, et al.			
	2002/0086497	07-04-2002	Kwok			
	5,960,297	09-28-1999	Saki			
	6,403,486	06-11-2002	Lou			
	6,284,623	09-04-2001	Zhang et al.			
	2003/0032261	02-13-2003	Yeh et al.			
	2003/0057184	03-27-2003	Yu et al.			
	6,265,317	07-24-2001	Chiu et al.			
	2003/0067035	04-10-2003	Tews et al.			
	6,461,936	10-08-2002	von Ehrenwall			
	6,319,794	11-20-2001	Akatsu et al.			
	2001/0009784	07-26-2001	Ma et al.			

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						YES
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<i>Shane L</i>	<i>4/30/05</i>

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JUN 28 2004

Group:  
2812

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**U.S. PATENT DOCUMENTS**

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EXAMINERS INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	

## FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
SDF	2000-269466	09-29-2000	Japan			<input checked="" type="checkbox"/> Abstract	<input type="checkbox"/>
SDF	57-80733	05-20-1982	Japan			<input checked="" type="checkbox"/> Abstract	<input type="checkbox"/>

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

- | OTHER ART (including SDF) |  |   |
|---------------------------|--|---|
|                           |  | Kern Rim, et al., "Transconductance Enhancement in Deep Submicron Strained-Si <i>n</i> -MOSFETs", International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998.                         |
|                           |  | Kern Rim, et al., "Characteristics and Device Design of Sub-100 nm Strained Si N- and PMOSFETs", 2002 Symposium On VLSI Technology Digest of Technical Papers, IEEE, pp 98-99.                    |
|                           |  | Gregory Scott, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress", International Electron Devices Meeting, 34.4.1, IEEE, September 1999.      |
|                           |  | F. Ootsuka, et al., "A Highly Dense, High-Performance 130nm node CMOS Technology for Large Scale System-on-a-Chip Application", International Electron Devices Meeting, 23.5.1, IEEE, April 2000. |
|                           |  | Shinya Ito, et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design", International Electron Devices Meeting, 10.7.1, IEEE, April 2000.         |
|                           |  | A. Shimizu, et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement", International Electron Devices Meeting, IEEE, March 2001.                          |
|                           |  | K. Ota, et al., "Novel Locally Strained Channel Technique for high Performance 55nm CMOS", International Electron Devices Meeting, 2.2.1, IEEE, February 2002.                                    |

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*Janette L.*  
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